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**INFORMATION DISCLOSURE
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First Named Inventor	Gaetan L. Mathieu
Group Art Unit	3726
Examiner Name	Rick K. Chang
Attorney Docket No.	P114-US

U.S. PUBLISHED PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant	Publ./Issue Date	Related [#]	Copy Enclosed
		Number	Kind Code ²				
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	2.	7102085		Ohta, et al.	9/2006		No ^{***}
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OTHER PRIOR ART – NONPATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ⁶	Copy Enclosed
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	188.	Karl F. Zimmerman, "SiProbe-A New Technology for Wafer Probing", proceedings, 1995, International Test Conference, pages 106-112 (MJC1975652-58).		Yes
	189.	United States International Trade Commission, In the Matter of Certain Probe Card Assemblies, Components Thereof and Certain Tested DRAM and NAND Flash Memory Devices and Products Containing Same, Inv. No. 337-TA-621, Respondent Micronics Japan Co., LTD's First Supplemental Response to Complainant FormFactor, Inc.'s First Set of Interrogatories (Nos. 25-29), Exhibit 5, March 14, 2008.		Yes
	190.	United States International Trade Commission, In the Matter of Certain Probe Card Assemblies, Components Thereof and Certain Tested DRAM and NAND Flash Memory Devices and Products Containing Same, Investigation No. 337-TA-621, Supplemental Response of Phicom Corporation to Complainant FormFactor, Inc.'s First Set of Interrogatories (Nos. 26-30), Exhibit 29, March 14, 2008		Yes
	191.	"Development of Manufacturing Process Membrane Probe Card", Korean Institute of Machinery and Materials, May 1992		Yes
	192.	C. Barsotti et al., "Very High Density Probing", 1988		Yes

Examiner Signature	Date Considered
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

** Reference cited in parent application US Serial Nos. 09/527,931. (See 1.98(d).)

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